

**Search Notes**

Application/Control No.

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Examiner

Ba Huynh

Applicant(s)/Patent under  
Reexamination

FUJII ET AL.

Art Unit

2179

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: USpat, USpgpub, EPO, Jpo, Derwent, IBM-tdb files search updated	1/10/2007	HB